

SLP65R700SJ/SLF65R700SJ 650V N-Channel MOSFET

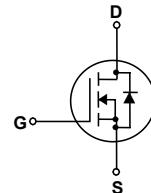
General Description

This Power MOSFET is produced using Maple semi's Advanced Super-Junction technology. This advanced technology has been especially tailored to minimize conduction loss, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for AC/DC power conversion in switching mode operation for higher efficiency.

Features

- 7A, 650V, $R_{DS(on)}$ typ. = 0.6Ω @ $V_{GS} = 10\text{ V}$
- Low gate charge (typical 25nC)
- High ruggedness
- Fast switching
- 100% avalanche tested
- Improved dv/dt capability


TO-220

G D S


Absolute Maximum Ratings

$T_c = 25^\circ\text{C}$ unless otherwise noted

Symbol	Parameter	SLP65R700SJ	SLF65R700SJ	Units	
V_{DSS}	Drain-Source Voltage	650		V	
I_D	Drain Current - Continuous ($T_c = 25^\circ\text{C}$)	7	7*	A	
	- Continuous ($T_c = 100^\circ\text{C}$)	5	5*	A	
I_{DM}	Drain Current - Pulsed	(Note 1)	10	10*	A
V_{GSS}	Gate-Source Voltage		± 30	V	
EAS	Single Pulsed Avalanche Energy	(Note 2)	86	mJ	
I_{AR}	Avalanche Current	(Note 1)	1.7	A	
E_{AR}	Repetitive Avalanche Energy	(Note 1)	43	mJ	
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	4.5	V/ns	
P_D	Power Dissipation ($T_c = 25^\circ\text{C}$)	205	35	W	
	- Derate above 25°C	1.67	0.3	W/ $^\circ\text{C}$	
T_J, T_{STG}	Operating and Storage Temperature Range		-55 to +150	$^\circ\text{C}$	
T_L	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		300	$^\circ\text{C}$	

* Drain current limited by maximum junction temperature.

Thermal Characteristics

Symbol	Parameter	SLP65R700SJ	SLF65R700SJ	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	0.6	3.6	$^\circ\text{C}/\text{W}$
$R_{\theta JS}$	Thermal Resistance, Case-to-Sink Typ.	0.5	--	$^\circ\text{C}/\text{W}$
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	62	62	$^\circ\text{C}/\text{W}$

Electrical Characteristics $T_C = 25^\circ\text{C}$ unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Typ	Max	Units
Off Characteristics						
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}, T_J=25^\circ\text{C}$	650	--	--	V
		$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}, T_J=150^\circ\text{C}$	--	700	--	V
$\Delta BV_{DSS} / \Delta T_J$	Breakdown Voltage Temperature Coefficient	$I_D = 250 \mu\text{A}$, Referenced to 25°C	--	0.6	--	V/ $^\circ\text{C}$
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 650 \text{ V}, V_{GS} = 0 \text{ V}$	--	--	1	μA
		$V_{DS} = 480 \text{ V}, T_C = 125^\circ\text{C}$	--	--	10	μA
I_{GSSF}	Gate-Body Leakage Current, Forward	$V_{GS} = 30 \text{ V}, V_{DS} = 0 \text{ V}$	--	--	100	nA
I_{GSSR}	Gate-Body Leakage Current, Reverse	$V_{GS} = -30 \text{ V}, V_{DS} = 0 \text{ V}$	--	--	-100	nA
On Characteristics						
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250 \mu\text{A}$	2.5	3.5	4.5	V
$R_{DS(\text{on})}$	Static Drain-Source On-Resistance	$V_{GS} = 10 \text{ V}, I_D = 3.5 \text{ A}$	--	0.6	0.7	Ω
g_{FS}	Forward Transconductance	$V_{DS} = 40 \text{ V}, I_D = 3.5 \text{ A}$ (Note 4)	--	16	--	S
Dynamic Characteristics						
C_{iss}	Input Capacitance	$V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V}, f = 1.0 \text{ MHz}$	--	360	--	pF
C_{oss}	Output Capacitance		--	25	--	pF
C_{rss}	Reverse Transfer Capacitance		--	1.2	--	pF
Switching Characteristics						
$t_{d(on)}$	Turn-On Delay Time	$V_{DD} = 400 \text{ V}, I_D = 3.5 \text{ A}, R_G = 20 \Omega$ (Note 4, 5)	--	25	--	ns
t_r	Turn-On Rise Time		--	55	--	ns
$t_{d(off)}$	Turn-Off Delay Time		--	70	--	ns
t_f	Turn-Off Fall Time		--	40	--	ns
Q_g	Total Gate Charge	$V_{DS} = 480 \text{ V}, I_D = 7 \text{ A}, V_{GS} = 10 \text{ V}$ (Note 4, 5)	--	8	--	nC
Q_{gs}	Gate-Source Charge		--	2.0	--	nC
Q_{gd}	Gate-Drain Charge		--	2.7	--	nC
Drain-Source Diode Characteristics and Maximum Ratings						
I_S	Maximum Continuous Drain-Source Diode Forward Current	--	--	7	--	A
I_{SM}	Maximum Pulsed Drain-Source Diode Forward Current	--	--	18	--	A
V_{SD}	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_S = 7 \text{ A}$	--	--	1.5	V
t_{rr}	Reverse Recovery Time	$V_{GS} = 0 \text{ V}, I_S = 7 \text{ A}, dI_F / dt = 100 \text{ A/us}$ (Note 4)	--	190	--	ns
Q_{rr}	Reverse Recovery Charge		--	2.3	--	uC

NOTES:

1. Repetitive Rating: Pulse width limited by maximum junction temperature
2. L=60mH, $I_{AS}=1.7\text{A}$, $V_{DD}=150\text{V}$, Starting $T_J=25^\circ\text{C}$
3. $I_{SS}\leq 7\text{A}$, $dI/dt \leq 200\text{A/us}$, $V_{DD} \leq BV_{DSS}$, Starting $T_J = 25^\circ\text{C}$
4. Pulse Test: Pulse width $\leq 300\mu\text{s}$, Duty Cycle $\leq 2\%$
5. Essentially Independent of Operating Temperature Typical Characteristics

Typical Characteristics

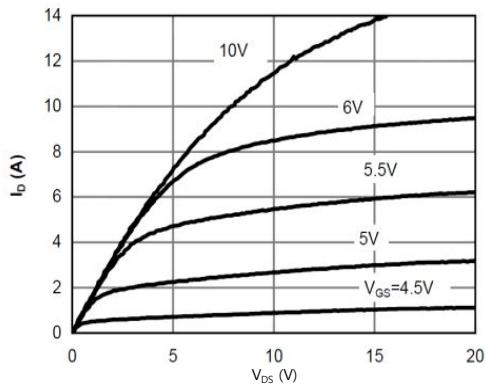


Figure 1: On-Region Characteristics@25°C

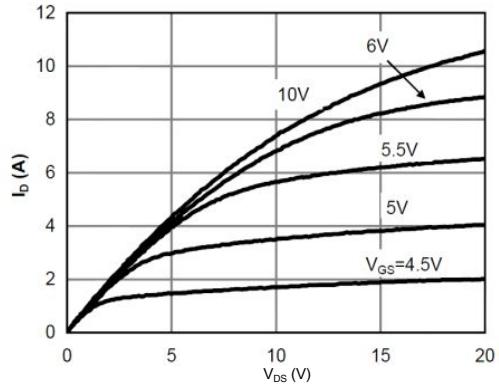


Figure 2: On-Region Characteristics@125°C

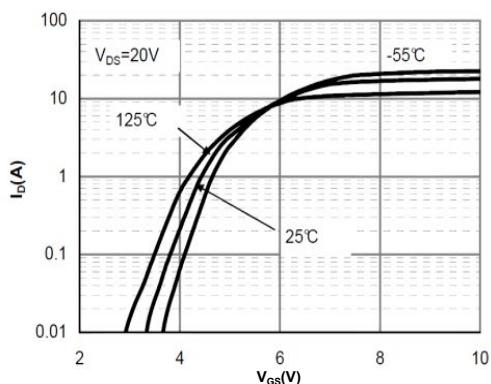


Figure 3: Transfer Characteristics

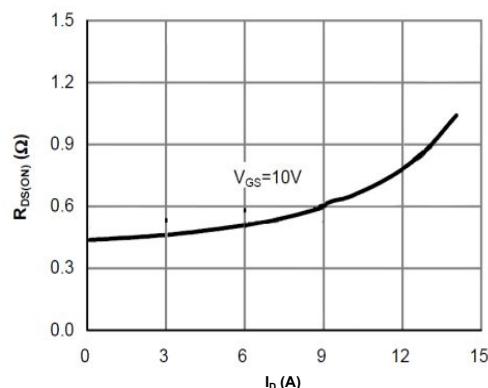


Figure 4: On-Resistance vs. Drain Current and Gate Voltage

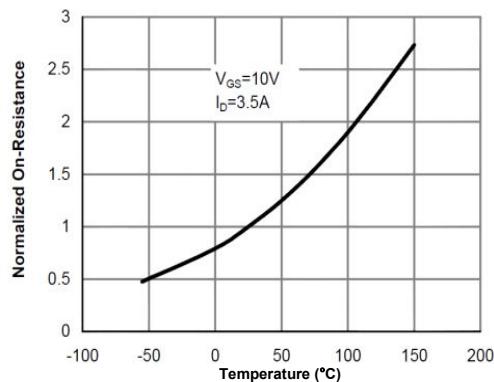


Figure 5: On-Resistance vs. Junction Temperature

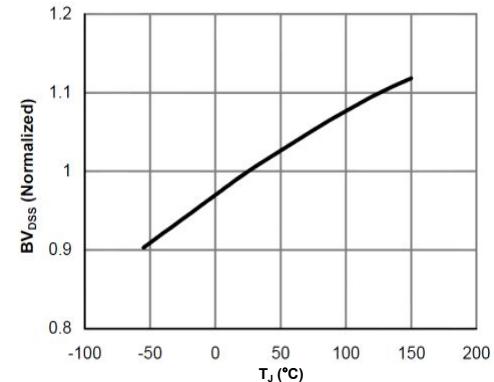


Figure 6: Break Down vs. Junction Temperature

Typical Characteristics

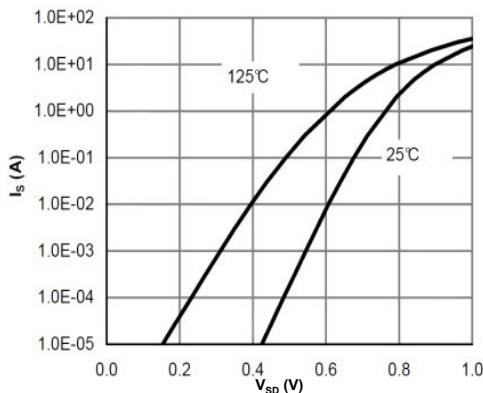


Figure 7: Body-Diode Characteristics

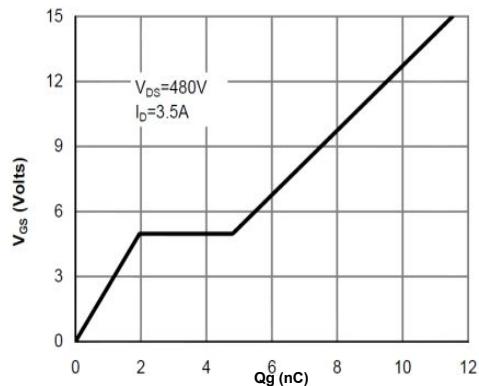


Figure 8: Gate-Charge Characteristics

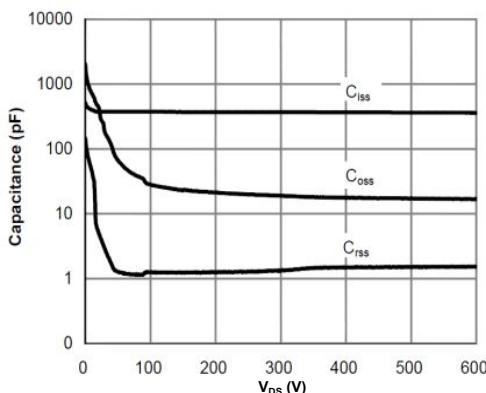


Figure 9: Capacitance Characteristics

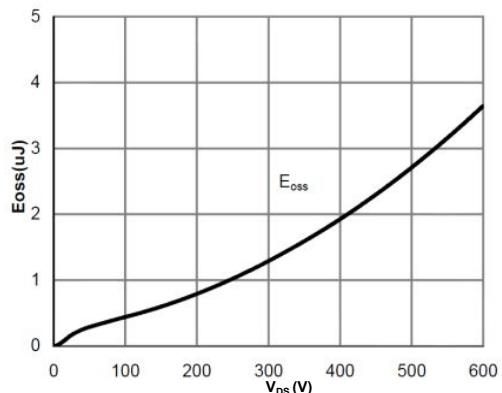


Figure 10: C_{oss} stored Energy

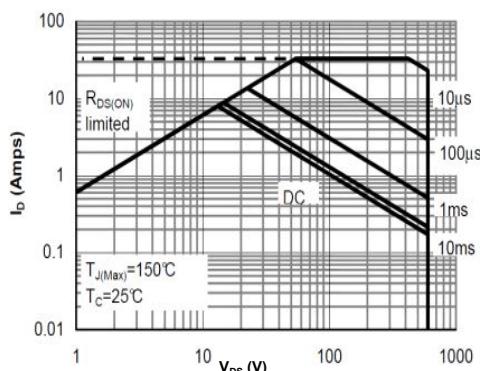


Figure 11: Maximum Forward Biased Safe Operating Area

Typical Characteristics

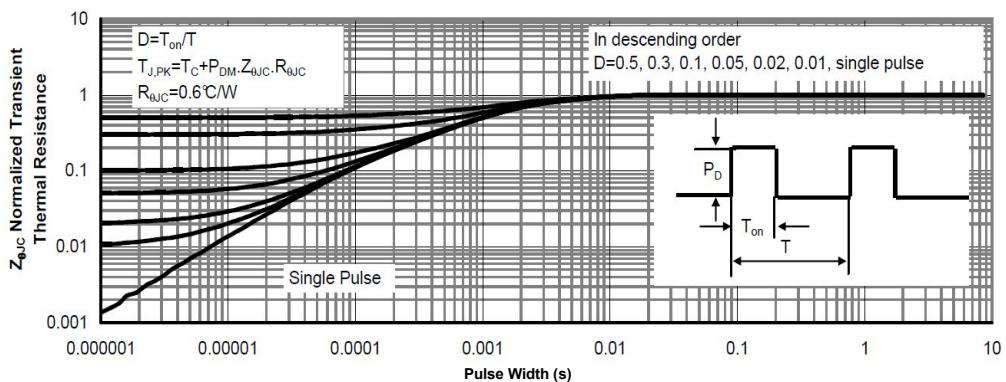


Figure 12: Normalized Maximum Transient Thermal Impedance

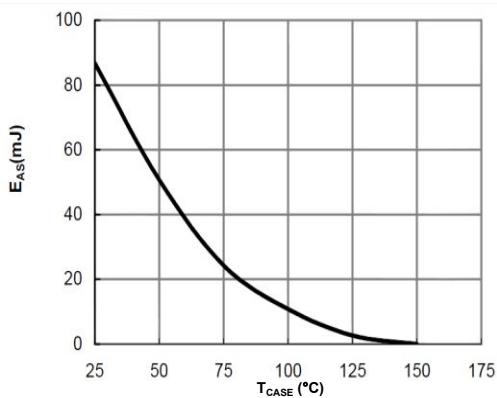


Figure 13: Avalanche energy

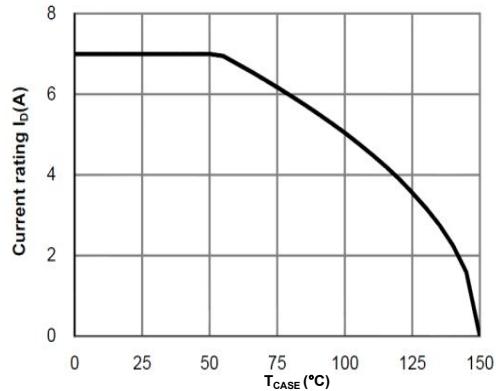


Figure 14: Current De-rating

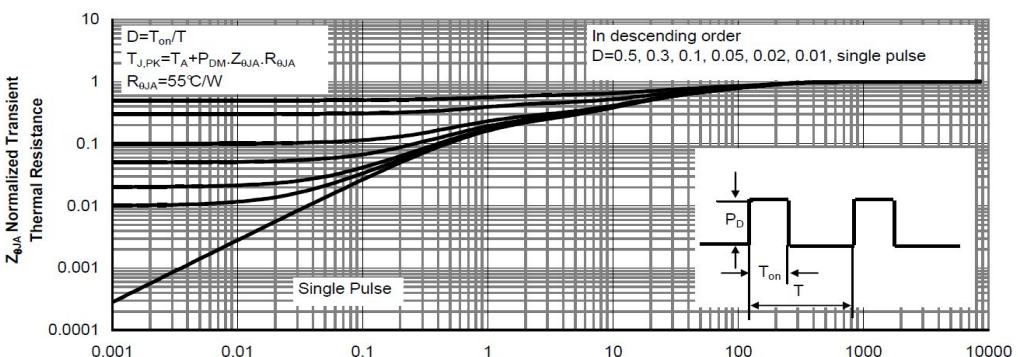
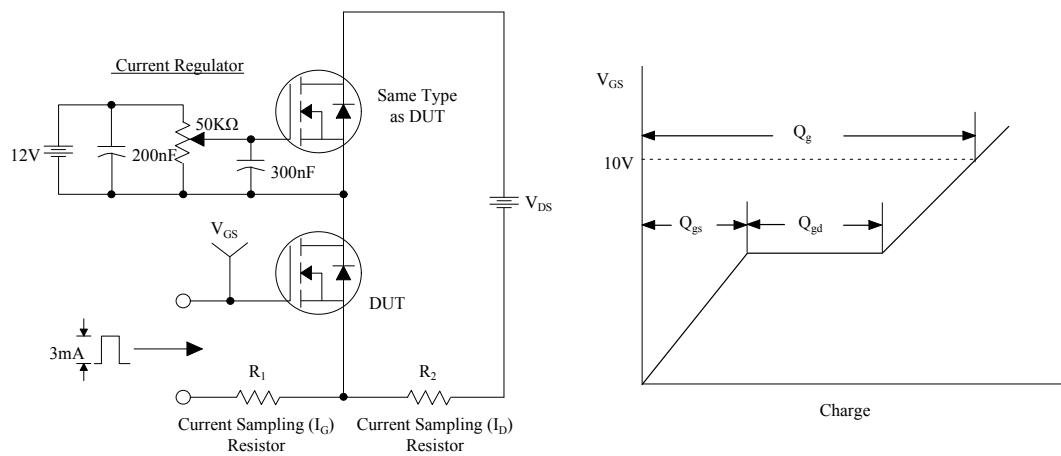
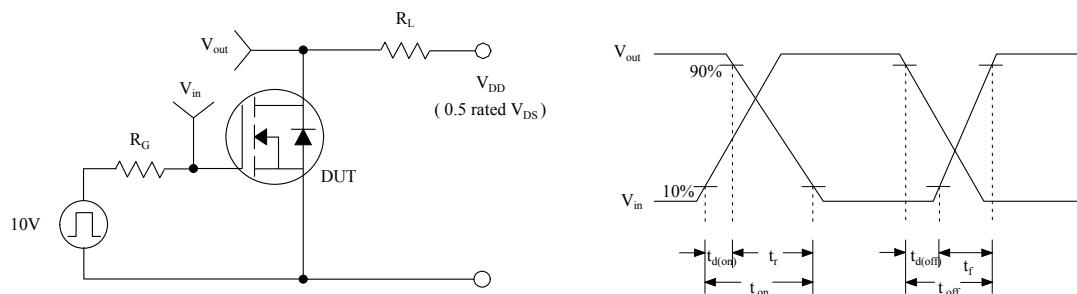


Figure 15: Normalized Maximum Transient Thermal Impedance

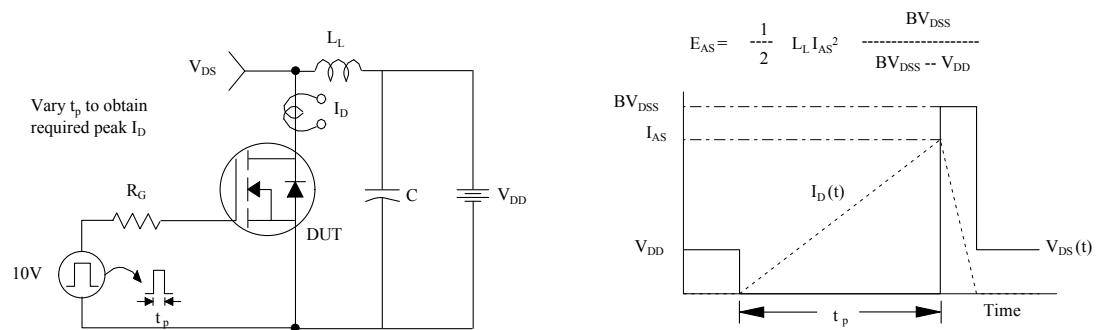
Gate Charge Test Circuit & Waveform



Resistive Switching Test Circuit & Waveforms



Unclamped Inductive Switching Test Circuit & Waveforms



Peak Diode Recovery dv/dt Test Circuit & Waveforms

